

ISO 5618-1:2023-11 (E)

Fine ceramics (advanced ceramics, advanced technical ceramics) - Test method for GaN crystal surface defects - Part 1: Classification of defects

Contents		Page
Foreword		iv
Introduction		v
1	Scope	1
2	Normative references	1
3	Terms and definitions	1
4	Classification of defects	3
4.1	General	3
4.2	Description of the defect classes	3
4.2.1	Dislocation	3
4.2.2	Process-induced defects	5
	Bibliography	7